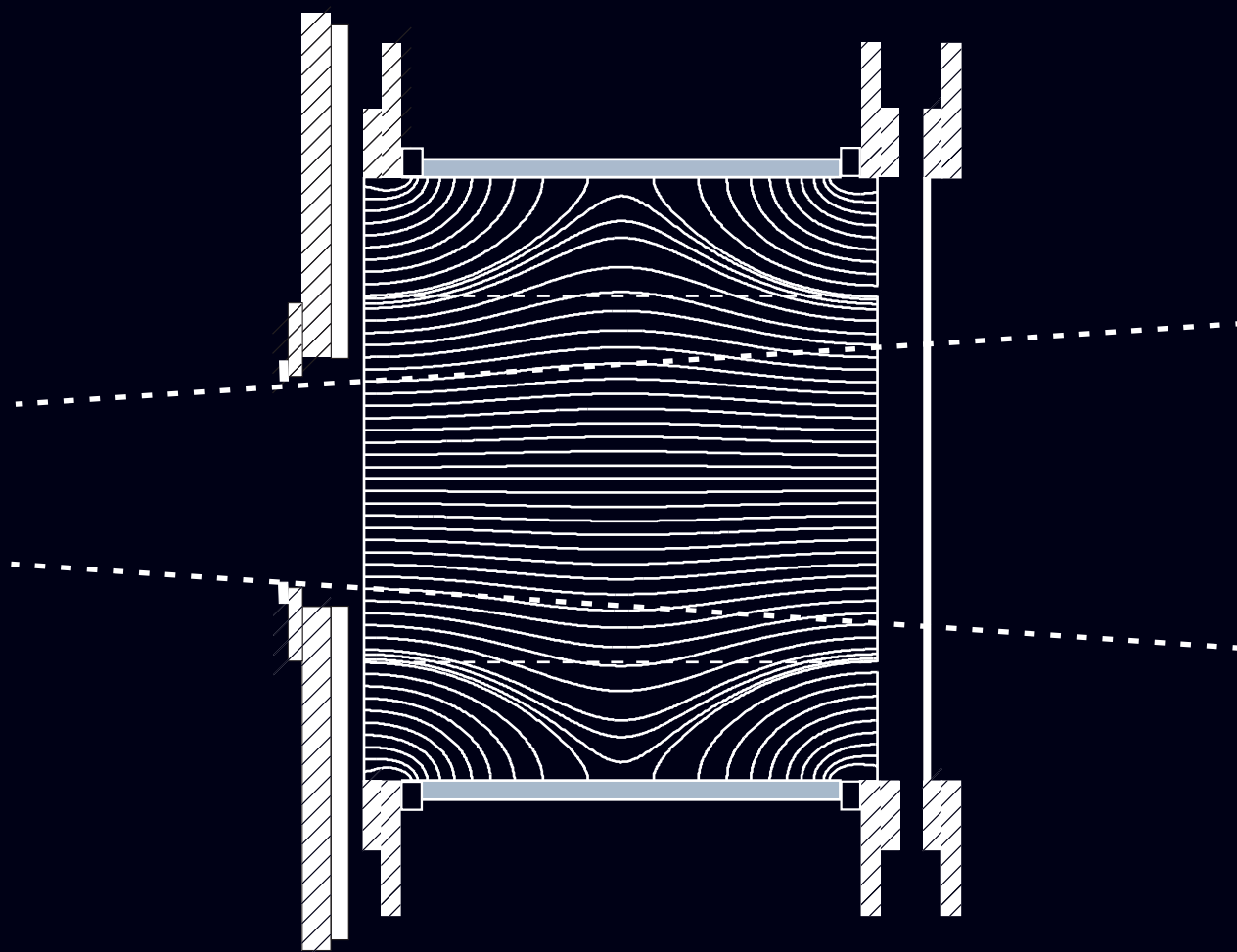


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- Statistical Engineering

¹At Boulder, CO 80303

²Some elements at Boulder, CO

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Cover: Schematic diagram of original wide-angle free-air chamber with the long middle electrode, showing the electric field lines. Structures of lead are indicated by white, aluminum by blue gray, and brass by cross hatching. Cover illustration arranged by C. Carey.

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